Appl. No. 10/643,545
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PATENT
Atty. Dkt. No. 83394.0012
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Amendments to the Specification:

Please insert the following paragraph before the paragraph beginning at page 16, line 10:

Fig. 18 illustrates an apparatus for analyzing mass spectrometric data according to embodiments of the present invention. The apparatus includes a first input means 32 for entering first data 31, a second input means 34 for entering second data 33, a first data storing means 35 for storing third data 36, and an evaluation (or calculation) means 37 for evaluating the candidates. The fourth data 38 outputted by the calculation means 37 is stored in a second data storing means 39. The first data 31 may be data measured by mass spectrometry for an ion to be analyzed. The second data 33 may be data measured by mass spectrometry for first to Nth dissociated ions of the ion. The third data 36 may be data of mass spectrometry for a plurality of candidates for the structure of ion. The evaluation means may include a first selection means 37a for selecting a first candidate for the structure of ion by making a comparison between the first data 31 and the third data 36 stored in the data storing means 35, and a second selection means 37b which provides a calculation value of mass spectrometry for a Mth candidate, where M is less than or equal to N, and makes a comparison between a measured value of mass spectrometry for a Mth dissociated ion entered through the second input means 34 and the calculation value, repeating from M equal to 1 to M equal to L, where L is equal to or greater than 2 and less than or equal to N, so that a (M+1)th candidate for the structure of ion can be selected.

Please replace the Abstract of the Disclosure with the replacement Abstract set forth on the next page.

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